

<b>Notice of References Cited</b>	Application/Control No. 09/966,824	Applicant(s)/Patent Under Reexamination RUEHLE ET AL. <span style="float: right;">97</span>	
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	C	US-5,377,264 ✓	12-1994	Lee et al.	713/189
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**NON-PATENT DOCUMENTS**

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